## Report for BACCN - Helsinky EPUAP 2025 Attendance

This year's programme was especially focused on critical and acute care, which made it particularly relevant to our work.

There were excellent sessions on a wide range of topics. Professor Worsley delivered an insightful talk related to medical devices and spinal collars, and there were many strong presentations on medical device-related pressure ulcers. One of the most thought-provoking parts of the programme centred around risk assessment tools in critical care. The discussions were rich and, at times, divided: some colleagues questioned the usefulness of risk assessment when nearly all ICU patients are already high risk, while others strongly advocated for structured tools. I learned there are far more available than I realised — including the Cubbin & Jackson, EVARUCI, COMHON Index, CALCULATE, RAPS-ICU, EFGU, and CAVE. This has given me a new perspective on how risk assessment might be applied and debated in our field.

The conference also saw the launch of new initiatives, such as a project focusing on patients with recurrent pressure ulcers, particularly those with spinal cord injury, and a new e-learning platform on the EPUAP website. Both reflect how the field is moving forward, with resources designed by experienced academics and educators.

I was proud to contribute to the meeting by presenting my NIHR Internship service evaluation, which explored the impact of tissue viability ward rounds and dedicated input in critical care. This project achieved a 40% reduction in hospital-acquired pressure injuries and was well received by delegates, highlighting the value of nursing-led initiatives.

Overall, the conference provided me with valuable ideas and contacts, and it was motivating to see critical care nursing so well represented in the programme. I am very grateful to BACCN for making my attendance possible. Thanks to your support, I am returning with fresh knowledge, inspiration, and practical ideas to take forward in our practice.





